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Form 449 (Modified)

Information Disclosure
Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No.

SUN1P231C1

Applicant:

Click Jr. et al.

Filing Date

2/20/2003

Application No.:

10/080,793

Group

2122

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
CP	A	6,202,208B1	3/2001	Holiday, Jr.	717	11	
	B	6,074,432	6/2000	Guccione	717	2	
	C	5,822,591	10/1998	Hochmuth	717	5	
	D	5,659,751	8/1997	Heninger	709	305	
	E	5,553,286	9/1996	Lee	717	5	
	F						
	G						
	H						
	I						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	J							
	K							
	L							
	M							
	N							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner	Date Considered	
Chau	02/18/05	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



Form 1449 (Modified)	Atty Docket No. SUN1P231C1	Application No.: 10/080,793
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Foreign Patent or Published Foreign Patent Application

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							Yes	No

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
CP	A	Rayside et al., "Change and Adaptive Maintenance Detection in Java Software Systems," Proceedings, IEEE Fifth Working Conference on Reverse Engineering, 1998, pp. 10-19.
Examiner Chaw		Date Considered 02/18/05

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.